

Search Notes

Application/Control No.

10/664,662

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

ISHIKAWA ET AL.

Art Unit

2681

SEARCHED

Class	Subclass	Date	Examiner
455	423	2/8/2006	HN
	436		
	437		
	442		
	434		
	439		
	502		
	127.1		
	127.5		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	2/8/2006	HN